

Data Sheet

FEATURES

Latch-up immune under all circumstances Human body model (HBM) ESD rating: 8 kV Low on resistance: 13.5 Ω ±9 V to ±22 V dual-supply operation 9 V to 40 V single-supply operation 48 V supply maximum ratings Fully specified at ±15 V, ±20 V, +12 V, and +36 V V_{DD} to V_{SS} analog signal range

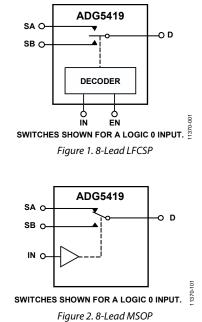
APPLICATIONS

High voltage signal routing Automatic test equipment Analog front-end circuits Precision data acquisition Industrial instrumentation Amplifier gain select Relay replacement

High Voltage Latch-Up Proof, Single SPDT Switch

ADG5419

FUNCTIONAL BLOCK DIAGRAMS



GENERAL DESCRIPTION

The ADG5419 is a monolithic industrial, complementary metal oxide semiconductor (CMOS) analog switch containing a latchup immune single-pole/double-throw (SPDT) switch.

Each switch conducts equally well in both directions when on, and each switch has an input signal range that extends to the power supplies. In the off condition, signal levels up to the supplies are blocked. The ADG5419 exhibits break-before-make switching action for use in multiplexer applications.

The ultralow on resistance and on-resistance flatness of these switches make them ideal solutions for data acquisition and gain switching applications where low distortion is critical. The latch-up immune construction and high ESD rating make these switches more robust in harsh environments.

PRODUCT HIGHLIGHTS

- 1. Trench isolation guards against latch-up. A dielectric trench separates the P channel and N channel transistors, thereby preventing latch-up even under severe overvoltage conditions.
- 2. Low R_{ON} of 13.5 Ω.
- 3. Dual-supply operation. For applications where the analog signal is bipolar, the ADG5419 can be operated from dual supplies up to ±22 V.
- 4. Single-supply operation. For applications where the analog signal is unipolar, the ADG5419 can be operated from a single-rail power supply up to 40 V.
- 5. 3 V logic compatible digital inputs: $V_{INH} = 2.0$ V, $V_{INL} = 0.8$ V.
- 6. No V_L logic power supply required.
- Available in 8-lead MSOP and 8-lead, 2 mm × 3 mm LFCSP packages.

Rev. A

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Comparable Parts

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Evaluation Kits

 Evaluation Board for 8 lead MSOP Devices in the Switch/ Mux Portfolio

Documentation 🖵

Data Sheet

• ADG5419: High Voltage Latch-Up Proof, Single SPDT Switch Data Sheet

User Guides

• UG-893: Evaluating the 8-Lead MSOP Devices in the Switch/Mux Portfolio

Reference Materials

Press

• Latch-up Immune, High ESD Switches, Expands ADI Offerings in High-Voltage Industrial Applications

Design Resources 🖵

- ADG5419 Material Declaration
- PCN-PDN Information
- Quality And Reliability
- Symbols and Footprints

Discussions 🖵

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REVISION HISTORY

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Changed Continuous Current, Sx or D to 8-Lead MSOP,	
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9/13—Revision 0: Initial Version

SPECIFICATIONS

±15 V DUAL SUPPLY

 V_{DD} = +15 V \pm 10%, V_{SS} = –15 V \pm 10%, GND = 0 V, unless otherwise noted.

Table 1.

Parameter	25°C	-40°C to +85°C	-40°C to +125°C	Unit	Test Conditions/Comments
ANALOG SWITCH					
Analog Signal Range			V _{DD} to V _{SS}	V	
On Resistance, Ron	13.5			Ωtyp	$V_{s} = \pm 10 V$, $I_{s} = -10 mA$; see Figure 27
	15	19	23	Ωmax	$V_{DD} = +13.5 \text{ V}, \text{ V}_{SS} = -13.5 \text{ V}$
On-Resistance Match Between Channels, ΔR_{ON}	0.1			Ωtyp	$V_{s} = \pm 10 V$, $I_{s} = -10 mA$
	0.8	1.3	1.4	Ωmax	
On-Resistance Flatness, RFLAT (ON)	1.8			Ωtyp	$V_{s} = \pm 10 V$, $I_{s} = -10 mA$
	2.2	2.7	3.1	Ωmax	
LEAKAGE CURRENTS					$V_{DD} = +16.5 \text{ V}, V_{SS} = -16.5 \text{ V}$
Source Off Leakage, Is (Off)	±0.1			nA typ	$V_S = \pm 10 \text{ V}$, $V_D = \mp 10 \text{ V}$; see Figure 24 and Figure 25
	±0.25	±1	±10	nA max	-
Drain Off Leakage, I _D (Off)	±0.1			nA typ	$V_s = \pm 10 \text{ V}, V_D = \mp 10 \text{ V}; \text{ see Figure 25}$
-	±0.4	±4	±10	nA max	
Channel On Leakage, I_D (On), I_S (On)	±0.1			nA typ	$V_S = V_D = \pm 10 \text{ V}$; see Figure 24 and Figure 26
	±0.4	±4	±10	nA max	
DIGITAL INPUTS					
Input High Voltage, V _{INH}			2.0	V min	
Input Low Voltage, V _{INL}			0.8	V max	
Input Current, IINL or IINH	0.002			μA typ	$V_{IN} = V_{GND} \text{ or } V_{DD}$
			±0.1	µA max	
Digital Input Capacitance, C _{IN}	6			pF typ	
DYNAMIC CHARACTERISTICS ¹					
Transition Time, transition	217			ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$
	260	310	336	ns max	$V_s = 10 V$; see Figure 32
t _{on} (EN)	179			ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$
	212	261	298	ns max	$V_s = 10 V$; see Figure 33
t _{off} (EN)	153			ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$
	176	195	209	ns max	$V_s = 10 V$; see Figure 33
Break-Before-Make Time Delay, t _D	86			ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$
			45	ns min	V _s = 10 V; see Figure 34
Charge Injection, Q _{INJ}	130			pC typ	$V_s = 0 V$, $R_s = 0 \Omega$, $C_L = 1 nF$; see Figure 35
Off Isolation	-60			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; see Figure 29
Channel-to-Channel Crosstalk	-80			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; see Figure 28
Total Harmonic Distortion + Noise	0.01			% typ	R_L = 1 k $\Omega,$ 15 V p-p, f = 20 Hz to 20 kHz; see Figure 30
–3 dB Bandwidth	190			MHz typ	$R_L = 50 \Omega$, $C_L = 5 pF$; see Figure 31
Insertion Loss	-0.8			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; see Figure 31
C _s (Off)	12			pF typ	$V_{s} = 0 V, f = 1 MHz$
C _D (Off)	23			pF typ	$V_{s} = 0 V, f = 1 MHz$
C _D (On), C _s (On)	55			pF typ	$V_{s} = 0 V, f = 1 MHz$
POWER REQUIREMENTS					$V_{DD} = +16.5 \text{ V}, \text{ V}_{SS} = -16.5 \text{ V}$
I _{DD}	45			μA typ	Digital inputs = $0 V \text{ or } V_{DD}$
	55		70	μA max	
I _{ss}	0.001			μA typ	Digital inputs = 0 V or V_{DD}
			1	μA max	
V _{DD} /V _{SS}			±9/±22	V min/V max	GND = 0 V

±20 V DUAL SUPPLY

 V_{DD} = +20 V \pm 10%, V_{SS} = -20 V \pm 10%, GND = 0 V, unless otherwise noted.

Table 2.

Parameter	25°C	-40°C to +85°C	-40°C to +125°C	Unit	Test Conditions/Comments
ANALOG SWITCH					
Analog Signal Range			V _{DD} to V _{SS}	V	
On Resistance, Ron	12.5			Ωtyp	$V_{s} = \pm 15 V$, $I_{s} = -10 mA$; see Figure 27
	14	18	22	Ωmax	$V_{DD} = +18 \text{ V}, \text{ V}_{SS} = -18 \text{ V}$
On-Resistance Match Between Channels, ΔR_{ON}	0.1			Ωtyp	$V_{s} = \pm 15 V$, $I_{s} = -10 mA$
	0.8	1.3	1.4	Ωmax	
On-Resistance Flatness, R _{FLAT (ON)}	2.3			Ωtyp	$V_s = \pm 15 V$, $I_s = -10 mA$
	2.7	3.3	3.7	Ωmax	
LEAKAGE CURRENTS					$V_{DD} = +22 V, V_{SS} = -22 V$
Source Off Leakage, I _s (Off)	±0.1			nA typ	V_{S} = ±15 V, V_{D} = \mp 15 V; see Figure 24 and Figure 25
	±0.25	±1	±10	nA max	-
Drain Off Leakage, I _D (Off)	±0.1			nA typ	$V_s = \pm 15 \text{ V}, V_D = \mp 15 \text{ V}; \text{ see Figure 25}$
	±0.4	±4	±10	nA max	
Channel On Leakage, $I_{\rm D}$ (On), $I_{\rm S}$ (On)	±0.1			nA typ	$V_{s} = V_{D} = \pm 15 V$; see Figure 24 and Figure 26
	±0.4	±4	±10	nA max	5
DIGITAL INPUTS	1				
Input High Voltage, V _{INH}			2.0	V min	
Input Low Voltage, VINL			0.8	V max	
Input Current, I _{INL} or I _{INH}	0.002			μA typ	$V_{IN} = V_{GND} \text{ or } V_{DD}$
			±0.1	µA max	
Digital Input Capacitance, C _{IN}	6			pF typ	
DYNAMIC CHARACTERISTICS ¹					
Transition Time, t _{TRANSITION}	200			ns typ	$R_L = 300 \Omega, C_L = 35 pF$
	235	279	294	ns max	$V_s = 10 V$; see Figure 32
t _{on} (EN)	199			ns typ	$R_L = 300 \Omega, C_L = 35 pF$
	239	300	344	ns max	V _s = 10 V; see Figure 33
t _{off} (EN)	157			ns typ	$R_L = 300 \Omega, C_L = 35 pF$
	185	208	227	ns max	V _s = 10 V; see Figure 33
Break-Before-Make Time Delay, t _D	77			ns typ	$R_L = 300 \Omega, C_L = 35 pF$
			46	ns min	$V_s = 10 V$; see Figure 34
Charge Injection, QINJ	160			pC typ	$V_s = 0 V$, $R_s = 0 \Omega$, $C_L = 1 nF$; see Figure 35
Off Isolation	-60			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; see Figure 29
Channel-to-Channel Crosstalk	-80			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; see Figure 28
Total Harmonic Distortion + Noise	0.01			% typ	$R_L = 1 \text{ k}\Omega$, 20 V p-p, f = 20 Hz to 20 kHz; see Figure 30
–3 dB Bandwidth	190			MHz typ	$R_L = 50 \Omega$, $C_L = 5 pF$; see Figure 31
Insertion Loss	-0.7			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; see Figure 31
C _s (Off)	11			pF typ	$V_s = 0 V, f = 1 MHz$
C_{D} (Off)	22			pF typ	$V_s = 0 V, f = 1 MHz$
$C_{\rm D}$ (On), $C_{\rm s}$ (On)	55			pF typ	$V_s = 0 V, f = 1 MHz$
POWER REQUIREMENTS				10 212	$V_{DD} = +22 V, V_{SS} = -22 V$
IDD	50			µA typ	Digital inputs = $0 \text{ V or } V_{DD}$
-00	70		110	µA max	
lss	0.001			μA typ	Digital inputs = 0 V or V_{DD}
	0.001		1	µA max	
V _{DD} /V _{SS}			±9/±22	V min/V max	GND = 0 V

12 V SINGLE SUPPLY

 V_{DD} = 12 V \pm 10%, V_{SS} = 0 V, GND = 0 V, unless otherwise noted.

Table 3.

Parameter	25°C	-40°C to +85°C	-40°C to +125°C	Unit	Test Conditions/Comments
ANALOG SWITCH					
Analog Signal Range			$0 V$ to V_{DD}	V	
On Resistance, R _{ON}	26			Ωtyp	$V_s = 0 V$ to $10 V$, $I_s = -10 mA$; see Figure 27
	30	38	44	Ωmax	$V_{DD} = 10.8 V, V_{SS} = 0 V$
On-Resistance Match Between Channels, ΔR_{ON}	0.1			Ωtyp	$V_{\text{S}}=0~\text{V}~\text{to}~10~\text{V}, I_{\text{S}}=-10~\text{mA}$
	1	1.5	1.6	Ωmax	
On-Resistance Flatness, R _{FLAT (ON)}	5.5			Ωtyp	$V_{s} = 0 V$ to 10 V, $I_{s} = -10 \text{ mA}$
	6.8	8.3	12.3	Ωmax	
LEAKAGE CURRENTS					$V_{DD} = +13.2 \text{ V}, \text{ V}_{SS} = 0 \text{ V}$
Source Off Leakage, I_s (Off)	±0.1			nA typ	$V_s = 1 V$ to 10 V, $V_D = 10 V$ to 1 V; see Figure 24 and Figure 25
	±0.25	±1	±10	nA max	
Drain Off Leakage, I _D (Off)	±0.1			nA typ	VS = 1V to10 V, VD = 10 V to 1V; see Figure 25
	±0.4	±4	±10	nA max	
Channel On Leakage, I $_{\mathbb D}$ (On), I $_{\mathbb S}$ (On)	±0.1			nA typ	$V_s = V_D = 1 V$ to 10 V; see Figure 24 and Figure 26
	±0.4	±4	±10	nA max	
DIGITAL INPUTS					
Input High Voltage, V _{INH}			2.0	V min	
Input Low Voltage, VINL			0.8	V max	
Input Current, I _{INL} or I _{INH}	0.002			μA typ	$V_{IN} = V_{GND} \text{ or } V_{DD}$
			±0.1	μA max	
Digital Input Capacitance, C _{IN}	6			pF typ	
DYNAMIC CHARACTERISTICS ¹					
Transition Time, transition	333			ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$
	414	508	567	ns max	V _s = 8 V; see Figure 32
t _{on} (EN)	327			ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$
	410	526	612	ns max	Vs = 8 V; see Figure 33
t _{off} (EN)	166			ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$
	200	528	611	ns max	V _s = 8 V; see Figure 33
Break-Before-Make Time Delay, t _D	176			ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$
			97	ns min	V _s = 8 V; see Figure 34
Charge Injection, Q _{INJ}	55			pC typ	$V_s = 6 V$, $R_s = 0 \Omega$, $C_L = 1 nF$; see Figure 35
Off Isolation	-60			dB typ	R_L = 50 $\Omega,$ C_L = 5 pF, f = 1 MHz; see Figure 29
Channel-to-Channel Crosstalk	-80			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; see Figure 28
Total Harmonic Distortion + Noise	0.03			% typ	R_L = 1 k $\Omega,$ 6 V p-p, f = 20 Hz to 20 kHz; see Figure 30
-3 dB Bandwidth	170			MHz typ	$R_L = 50 \Omega$, $C_L = 5 pF$; see Figure 31
Insertion Loss	-1.7			dB typ	R_L = 50 $\Omega,$ C_L = 5 pF, f = 1 MHz; see Figure 31
C _s (Off)	15			pF typ	$V_{s} = 6 V, f = 1 MHz$
C _D (Off)	29			pF typ	$V_{s} = 0 V, f = 1 MHz$
C _D (On), C _s (On)	50			pF typ	$V_{s} = 6 V, f = 1 MHz$
POWER REQUIREMENTS					V _{DD} = 13.2 V
l _{DD}	40 50		65	μA typ μA max	Digital inputs = $0 V \text{ or } V_{DD}$
	55		9/40	V min/V max	$GND = 0 V, V_{SS} = 0 V$

36 V SINGLE SUPPLY

 V_{DD} = 36 V \pm 10%, V_{SS} = 0 V, GND = 0 V, unless otherwise noted.

Table 4.

Parameter	25°C	-40°C to +85°C	-40°C to +125°C	Unit	Test Conditions/Comments
ANALOG SWITCH					
Analog Signal Range			$0 V to V_{DD}$	V	
On Resistance, R _{ON}	14.5			Ωtyp	Vs = 0 V to 30 V, Is = -10 mA; see Figure 27
	16	20	24	Ωmax	$V_{DD} = 32.4 \text{ V}, V_{SS} = 0 \text{ V}$
On-Resistance Match Between Channels, ΔR _{ON}	0.1			Ωtyp	$V_{s} = 0 V$ to 30 V, $I_{s} = -10 \text{ mA}$
	0.8	1.3	1.4	Ωmax	
On-Resistance Flatness, R _{FLAT (ON)}	3.5			Ωtyp	$V_s = 0 V$ to 30 V, $I_s = -10 mA$
	4.3	5.5	6.5	Ωmax	
LEAKAGE CURRENTS					$V_{DD} = 39.6 \text{ V}, \text{ V}_{SS} = 0 \text{ V}$
Source Off Leakage, I _s (Off)	±0.1			nA typ	V_{S} = 1 V to 30 V, V_{D} = 30 V to 1 V; see Figure 24 and Figure 25
	±0.25	±1	±10	nA max	
Drain Off Leakage, I _D (Off)	±0.1			nA typ	V_{S} = 1V to 30 V, V_{D} = 30 V to 1V; see Figure 25
	±0.4	±4	±10	nA max	
Channel On Leakage, I $_{\rm D}$ (On), I $_{\rm S}$ (On)	±0.1			nA typ	$V_S = V_D = 1$ V to 30 V; see Figure 24 and Figure 26
	±0.4	±4	±10	nA max	
DIGITAL INPUTS					
Input High Voltage, V _{INH}			2.0	V min	
Input Low Voltage, VINL			0.8	V max	
Input Current, I _{INL} or I _{INH}	0.002			μA typ	$V_{IN} = V_{GND} \text{ or } V_{DD}$
			±0.1	μA max	
Digital Input Capacitance, C _{IN}	6			pF typ	
DYNAMIC CHARACTERISTICS ¹					
Transition Time, transition	216			ns typ	$R_L = 300 \Omega, C_L = 35 pF$
	250	286	310	ns max	Vs = 18 V; see Figure 32
t _{on} (EN)	199			ns typ	$R_L = 300 \Omega, C_L = 35 pF$
	232	279	315	ns max	V _s = 18 V; see Figure 33
t _{off} (EN)	160			ns typ	$R_L = 300 \Omega, C_L = 35 pF$
	193	284	315	ns max	V _s = 18 V; see Figure 33
Break-Before-Make Time Delay, t_{D}	80			ns typ	$R_L = 300 \Omega, C_L = 35 pF$
			47	ns min	Vs = 18 V; see Figure 34
Charge Injection, Q _{INJ}	135			pC typ	$V_s = 18 \text{ V}, \text{ R}_s = 0 \Omega, \text{ C}_L = 1 \text{ nF}; \text{ see}$ Figure 35
Off Isolation	-60			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; see Figure 29
Channel-to-Channel Crosstalk	-80			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; see Figure 28
Total Harmonic Distortion + Noise	0.01			% typ	R_L = 1 k Ω , 18 V p-p, f = 20 Hz to 20 kHz; see Figure 30
–3 dB Bandwidth	170			MHz typ	$R_L = 50 \Omega$, $C_L = 5 pF$; see Figure 31
Insertion Loss	-1			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; see Figure 31
Cs (Off)	14			pF typ	$V_{s} = 18 V, f = 1 MHz$
C _D (Off)	26			pF typ	$V_s = 0 V$, $f = 1 MHz$
C _D (On), C _s (On)	50			pF typ	$V_{s} = 18 V, f = 1 MHz$
POWER REQUIREMENTS					V _{DD} = 39.6 V
DD	80 100		130	μA typ μA max	Digital inputs = $0 V \text{ or } V_{DD}$
V _{DD}	1.20		9/40	V min/V max	$GND = 0 V, V_{ss} = 0 V$

CONTINUOUS CURRENT PER CHANNEL, Sx OR D

Table 5.

Parameter	25°C	85°C	125°C	Unit	Test Conditions/Comments
8-LEAD MSOP					$\theta_{JA} = 133.1^{\circ}C/W$
$V_{DD} = 15 \text{ V}, V_{SS} = -15 \text{ V}$	113	73	46	mA maximum	
$V_{DD} = 20 \text{ V}, \text{ V}_{SS} = -20 \text{ V}$	118	76	47	mA maximum	
$V_{DD} = 12 V, V_{SS} = 0 V$	90	60	41	mA maximum	
$V_{DD} = 36 V, V_{SS} = 0 V$	116	74	46	mA maximum	
8-LEAD LFCSP					$\theta_{JA} = 60.88^{\circ}C/W$
$V_{DD} = 15 V, V_{SS} = -15 V$	156	92	52	mA maximum	
$V_{DD} = 20 \text{ V}, \text{ V}_{SS} = -20 \text{ V}$	163	95	53	mA maximum	
$V_{DD} = 12 V, V_{SS} = 0 V$	126	78	48	mA maximum	
$V_{DD} = 36 V, V_{SS} = 0 V$	160	93	53	mA maximum	

ABSOLUTE MAXIMUM RATINGS

 $T_A = 25^{\circ}C$, unless otherwise noted.

Table 6.

Table 0.	
Parameter	Rating
V _{DD} to V _{SS}	48 V
V _{DD} to GND	–0.3 V to +48 V
Vss to GND	+0.3 V to -48 V
Analog Inputs ¹	$V_{SS} - 0.3 V$ to $V_{DD} + 0.3 V$ or 30 mA, whichever occurs first
Digital Inputs ¹	V _{SS} – 0.3 V to V _{DD} + 0.3 V or 30 mA, whichever occurs first
Peak Current, Sx or D Pins	410 mA (pulsed at 1 ms, 10% duty cycle maximum)
Continuous Current, Sx or D ²	Data + 15%
Temperature Range	
Operating	–40°C to +125°C
Storage	–65°C to +150°C
Junction Temperature	150°C
Thermal Impedance, θ _{JA}	
8-Lead MSOP (4-Layer Board)	133.1°C/W
8-Lead LFCSP	60.88°C/W
Reflow Soldering Peak Temperature, Pb Free	As per JEDEC J-STD-020
Human Body Model (HBM) ESD	8 kV

¹ Overvoltages at the IN, Sx, and D pins are clamped by internal diodes. Limit current to the maximum ratings given.

² See Table 5.

Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

ESD CAUTION

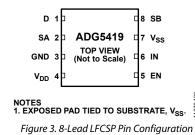


ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

PIN CONFIGURATIONS AND FUNCTION DESCRIPTIONS

8

1370-



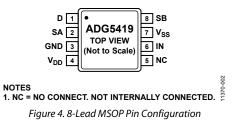


Table 7. Pin Function Descriptions

Pin No.			
LFCSP	MSOP	Mnemonic	Description
1	1	D	Drain Terminal. This pin can be an input or output.
2	2	SA	Source Terminal. This pin can be an input or an output.
3	3	GND	Ground (0 V) Reference.
4	4	V _{DD}	Most Positive Power Supply Potential.
5		EN	Active High Digital Input. When this pin is low, the device is disabled and all switches are turned off. When this pin is high, the IN logic input determines the state of the switch.
6	6	IN	Logic Control Input.
7	7	Vss	Most Negative Power Supply Potential.
8	8	SB	Source Terminal. This pin can be an input or an output.
	5	NC	No Connect. Not internally connected.
	Not applicable	EPAD	Exposed Pad. Exposed pad tied to substrate, Vss.

Table 8. LFCSP Truth Table

EN	IN	Switch A	Switch B
0	X ¹	Off	Off
1	0	On	Off
1	1	Off	On

 1 X = don't care.

Table 9. MSOP Truth Table

IN	Switch A	Switch B
0	On	Off
1	Off	On

ADG5419

TYPICAL PERFORMANCE CHARACTERISTICS

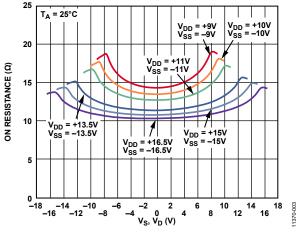


Figure 5. On Resistance as a Function of V_s, V_D Dual Supply

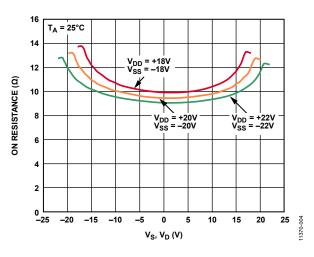


Figure 6. On Resistance as a Function of V_s, V_D Dual Supply)

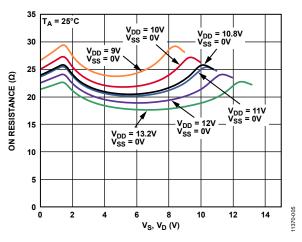


Figure 7. On Resistance as a Function of Vs, VD (Single Supply)

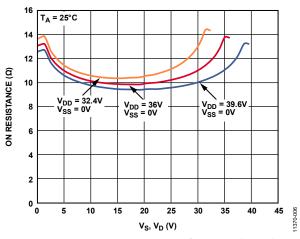


Figure 8. On Resistance as a Function of V_{S} , V_{D} (Single Supply)

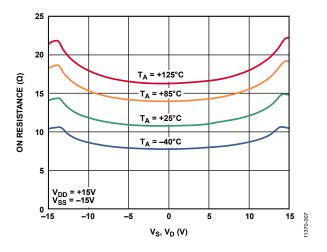


Figure 9. On Resistance as a Function of Vs (Vb) for Different Temperatures, ± 15 V Dual Supply

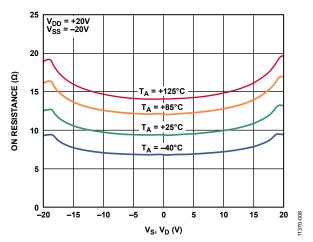


Figure 10. On Resistance as a Function of V_S (V_D) for Different Temperatures, ±20 V Dual Supply

Data Sheet

ADG5419

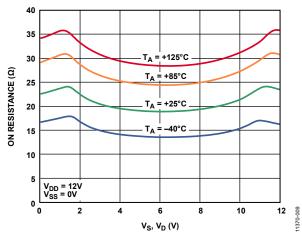


Figure 11. On Resistance as a Function of $V_S(V_D)$ for Different Temperatures, 12 V Single Supply

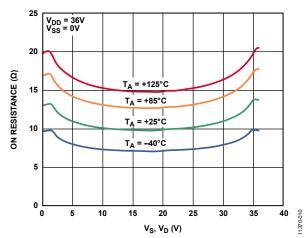


Figure 12. On Resistance as a Function of Vs $(V_{\rm D})$ for Different Temperatures, 36 V Single Supply

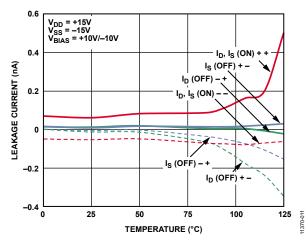


Figure 13. Leakage Currents as a Function of Temperature, ± 15 V Dual Supply

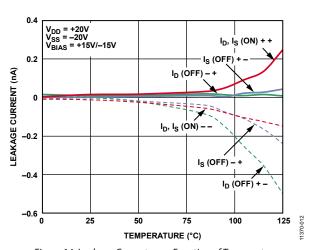


Figure 14. Leakage Currents as a Function of Temperature, ± 20 V Dual Supply

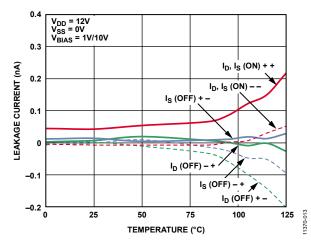
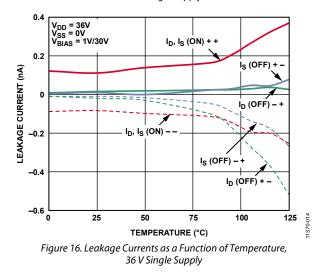
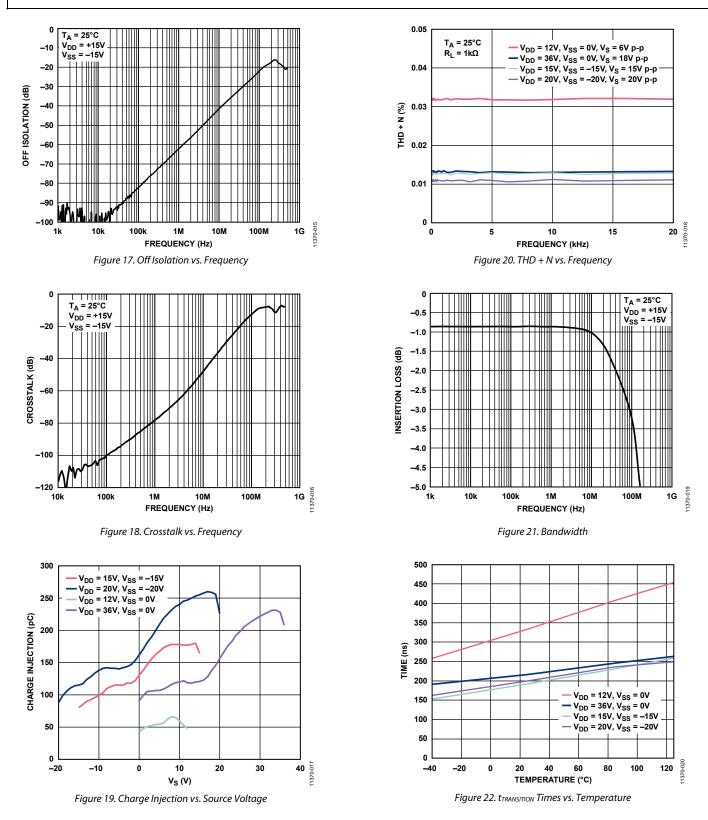


Figure 15. Leakage Currents as a Function of Temperature, 12 V Single Supply



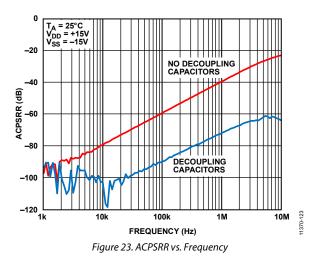
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TEST CIRCUITS

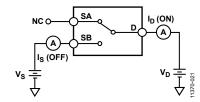
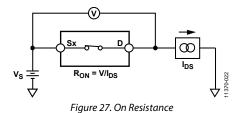


Figure 24. Channel On and Source Off Leakage (MSOP Only)



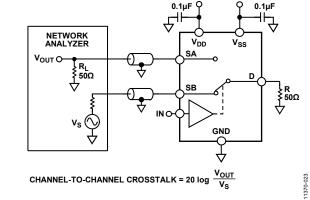
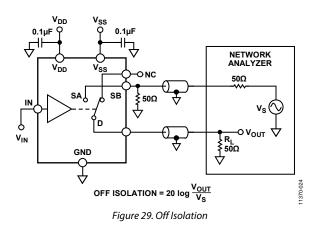


Figure 28. Channel-to-Channel Crosstalk



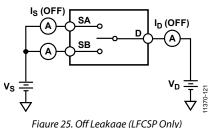


Figure 25. Off Leakage (LFCSP Only)

Figure 26. On Leakage (LFCSP Only)

I_D (ON)

Δ

VD

11370-122

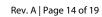
SA

SB -0

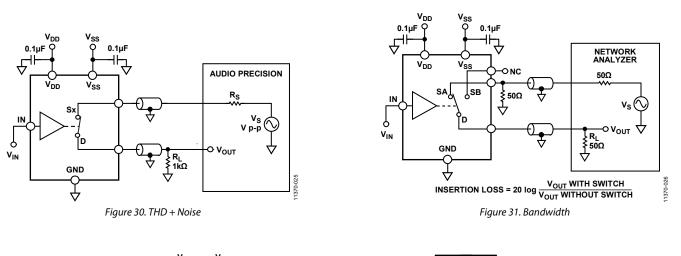
NCO

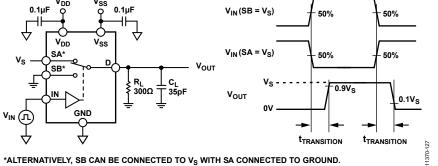
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*ALTERNATIVELY, SB CAN BE CONNECTED TO $\mathbf{V}_{\mathbf{S}}$ with sa connected to ground.

Figure 32. Transition Time, t_{TRANSITION}

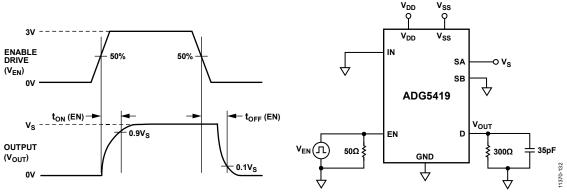


Figure 33. Enable Delay, ton (EN), toFF (EN) (LFCSP Only)

ADG5419

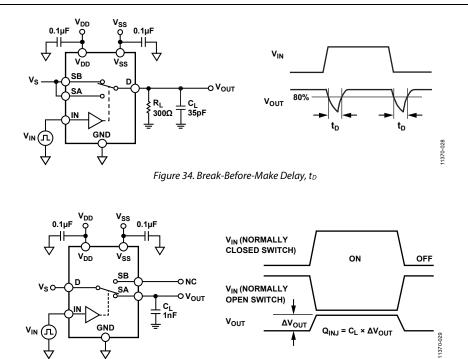


Figure 35. Charge Injection

 \uparrow

Idd

IDD represents the positive supply current.

Iss

Iss represents the negative supply current.

VD, Vs

 $V_{\rm D}$ and $V_{\rm S}$ represent the analog voltage on Terminal D and Terminal S, respectively.

Ron

 $R_{\rm ON}$ is the ohmic resistance between Terminal D and Terminal S.

ΔR_{ON}

 ΔR_{ON} represents the difference between the R_{ON} of any two channels.

RFLAT (ON)

The difference between the maximum and minimum value of on resistance as measured over the specified analog signal range is represented by $R_{\rm FLAT \ (ON)}$.

Is (Off)

Is (Off) is the source leakage current with the switch off.

I_D (Off)

 $I_{\rm D}$ (Off) is the drain leakage current with the switch off.

I_D (On), I_s (On)

 $I_{\rm D}$ (On) and $I_{\rm S}$ (On) represent the channel leakage currents with the switch on.

VINL

 $V_{\mbox{\scriptsize INL}}$ is the maximum input voltage for Logic 0.

VINH

 $V_{\mbox{\scriptsize INH}}$ is the minimum input voltage for Logic 1.

IINL, IINH

 $I_{\rm INL}$ and $I_{\rm INH}$ represent the low and high input currents of the digital inputs.

C_D (Off)

 C_D (Off) represents the off switch drain capacitance, which is measured with reference to ground.

C_s (Off)

 C_{s} (Off) represents the off switch source capacitance, which is measured with reference to ground.

C_D (On), C_S (On)

 $C_{\text{D}}\left(\text{On}\right)$ and $C_{\text{S}}\left(\text{On}\right)$ represent on switch capacitances, which are measured with reference to ground.

Cin

C_{IN} represents digital input capacitance.

ton (EN)

 $t_{\rm ON}$ represents the delay time between the 50% and 90% points of the digital input and switch on condition. See Figure 33.

toff (EN)

 t_{OFF} represents the delay time between the 50% and 90% points of the digital input and switch off condition. See Figure 33.

tTRANSITION

t_{TRANSITION} represents the delay time between the 50% and 90% points of the digital inputs and the switch on condition when switching from one address state to another.

t_D

 $t_{\rm D}$ represents the off time measured between the 80% point of both switches when switching from one address state to another.

Off Isolation

Off isolation is a measure of unwanted signal coupling through an off channel.

Charge Injection

Charge injection is a measure of the glitch impulse transferred from the digital input to the analog output during switching.

Crosstalk

Crosstalk is a measure of unwanted signal that is coupled through from one channel to another as a result of parasitic capacitance.

Bandwidth

Bandwidth is the frequency at which the output is attenuated by 3 dB, from its dc level.

Total Harmonic Distortion + Noise (THD + N)

THD + N is the ratio of the harmonic amplitude plus noise of the signal to the fundamental.

AC Power Supply Rejection Ratio (ACPSRR)

ACPSRR measures the ability of a device to avoid coupling noise and spurious signals that appear on the supply voltage pin to the output of the switch. The dc voltage on the device is modulated by a sine wave of 0.62 V p-p. The ratio of the amplitude of signal on the output to the amplitude of the modulation is the ACPSRR. See Figure 23.

APPLICATIONS INFORMATION

The ADG54xx family of switches and multiplexers provide a robust solution for instrumentation, industrial, aerospace, and other harsh environments that are prone to latch-up, which is an undesirable high current state that can lead to device failure and persists until the power supply is turned off. The ADG5419 high voltage switch allows single-supply operation from 9 V to 40 V and dual-supply operation from ±9 V to ±22 V. The ADG5419 (as well as other select devices within this family) achieves an 8 kV human body model ESD rating, which provides a robust solution, eliminating the need for separate protection circuitry designs in some applications.

TRENCH ISOLATION

In the ADG5419, an insulating oxide layer (trench) is placed between the NMOS and the PMOS transistors of each CMOS switch. Parasitic junctions, which occur between the transistors in junction-isolated switches, are eliminated, and the result is a completely latch-up immune switch.

In junction isolation, the N and P wells of the PMOS and NMOS transistors form a diode that is reverse-biased under normal operation. However, during overvoltage conditions, this diode can become forward-biased. The two transistors form a silicon-controlled rectifier (SCR) type circuit, causing a significant amplification of the current that, in turn, leads to latch-up. With trench isolation, this diode is removed, and the result is a latch-up immune switch.

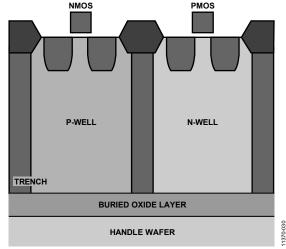
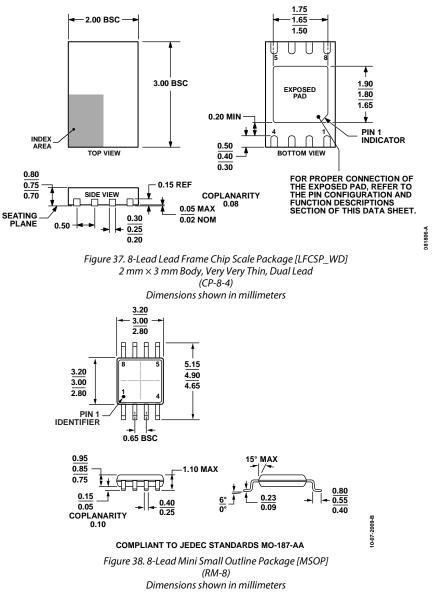


Figure 36. Trench Isolation

OUTLINE DIMENSIONS



ORDERING GUIDE

Model ¹	Temperature Range	Package Description	Package Option	Branding
ADG5419BCPZ-RL7	-40°C to +125°C	8-Lead Lead Frame Chip Scale Package [LFCSP_WD]	CP-8-4	BL
ADG5419BRMZ	-40°C to +125°C	8-Lead Mini Small Outline Package [MSOP]	RM-8	S48
ADG5419BRMZ-RL7	-40°C to +125°C	8-Lead Mini Small Outline Package [MSOP]	RM-8	S48

¹ Z = RoHS Compliant Part.

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